

January 1993 Revised March 2005

74ABT273 **Octal D-Type Flip-Flop**

General Description

The ABT273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset (MR) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the MR input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

Features

- Eight edge-triggered D-type flip-flops
- Buffered common clock
- Buffered, asynchronous Master Reset
- See ABT377 for clock enable version
- See ABT373 for transparent latch version
- See ABT374 for 3-STATE version
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Disable time less than enable time to avoid bus conten-

Ordering Code:

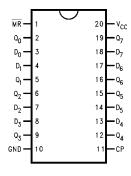
Order Number	Package Number	Package Description
74ABT273CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74ABT273CSJ	M20D	Pb-Free 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT273CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide
74ABT273CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74ABT273CMTCX_NL (Note 1)	MTC20	Pb-Free 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Pb-Free package per JEDEC J-STD-020B.

Note 1: "_NL" indicates Pb-Free package (per JEDEC J-STD-020B). Device available in Tape and Reel only.

Connection Diagram



Pin Descriptions

Pin Names	Description
D ₀ –D ₇	Data Inputs
$\frac{D_0-D_7}{MR}$	Master Reset (Active LOW)
СР	Clock Pulse Input (Active Rising Edge)
Q ₀ -Q ₇	Data Outputs

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DS011549

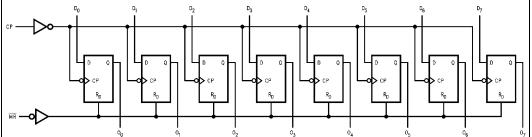
Truth Table

Operating Mode		Output		
	MR	СР	D _n	Q_n
Reset (Clear)	L	Х	Х	L
Load "1"	Н	~	h	Н
Load "0"	Н	~	I	L

- H = HIGH Voltage Level steady state
 h = HIGH Voltage Level one setup time prior to the LOW-to-HIGH clock transition
 L = LOW Voltage Level steady state
 I = LOW Voltage Level one setup time prior to the LOW-to-HIGH clock transition
 X = Immaterial

 = LOW-to-HIGH clock transition

Logic Diagram



 0_0 0_1 0_2 0_3 0_4 0_5 0_6 Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 2)

Recommended Operating Conditions

Storage Temperature —65°C to +150°C

Ambient Temperature under Bias —55°C to +125°C

Ambient Temperature under Bias -55° C to +125 $^{\circ}$ C Junction Temperature under Bias -55° C to +150 $^{\circ}$ C

V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to +4.75V in the HIGH State -0.5V to V_{CC}

Current Applied to Output

in LOW State (Max) $\qquad \qquad \text{twice the rated I_{OL} (mA)}$

DC Latchup Source Current -500 mA

(Across Comm Operating Range)

Over Voltage Latchup V_{CC} + 4.5V

Free Air Ambient Temperature -40°C to +85°C Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate (ΔV/Δt)

Data Input 50 mV/ns
Enable Input 20 mV/ns

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			8.0	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	2.5			V	Min	I _{OH} = -3 mA
		2.0			V	IVIIII	$I_{OH} = -32 \text{ mA}$
V _{OL}	Output LOW Voltage			0.55	V	Min	I _{OL} = 64 mA
I _{IH}	Input HIGH Current			1	μА	Max	V _{IN} = 2.7V (Note 4)
				1	μΑ	IVIAX	$V_{IN} = V_{CC}$
I _{BVI}	Input HIGH Current			7	μА	Max	V _{IN} = 7.0V
	Breakdown Test						
I _{IL}	Input LOW Current			-1	μА	Max	V _{IN} = 0.5V (Note 4)
				-1	μΑ		$V_{IN}=0.0V$
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA
							All Other Pins Grounded
Ios	Output Short-Circuit Current	-100		-275	mA	Max	V _{OUT} = 0.0V
I _{CEX}	Output HIGH Leakage Current			50	μА	Max	V _{OUT} = V _{CC}
I _{CCH}	Power Supply Current			50	μА	Max	All Outputs HIGH
I _{CCL}	Power Supply Current			30	mA	Max	All Outputs LOW
I _{CCT}	Maximum I _{CC} /Input Outputs Enabled			1.5	mA	Max	V _I = V _{CC} - 2.1V
							Data Input V _I = V _{CC} - 2.1V
							All Others at V _{CC} or GND
I _{CCD}	Dynamic I _{CC} No Load			0.3	mA/	Max	Outputs Open (Note 5)
					MHz	iviax	One Bit Toggling, 50% Duty Cycle

Note 4: Guaranteed but not tested.

Note 5: For 8 bits toggling, $I_{CCD} < 0.5 \ \text{mA/MHz}.$

AC Electrical Characteristics

(SSOIC package)

Symbol Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = -55$ °C to +125 °C $V_{CC} = 4.5$ V to 5.5V $C_L = 50$ pF		$T_{A} = -40^{\circ}\text{C to} + 85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to} 5.5\text{V}$ $C_{L} = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	150	200		150		150		MHz
t _{PLH}	Propagation Delay	2.0		6.0	1.0	7.0	2.0	6.0	ns
t _{PHL}	CP to O _n	2.8		6.8	1.0	7.5	2.8	6.8	115
t _{PHL}	Propagation Delay MR to On	2.5		7.4	1.0	8.2	2.5	7.4	ns

AC Operating Requirements

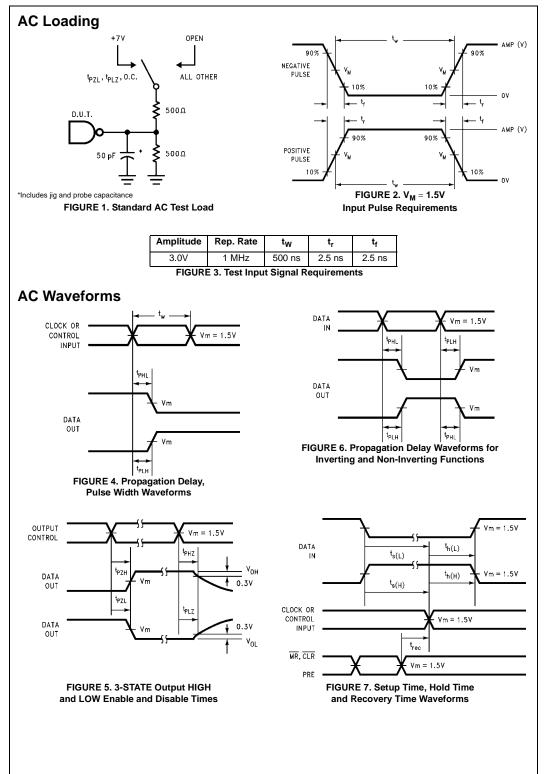
Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		$T_{A} = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_{L} = 50 \text{ pF}$		Units	
		Min	Max	Min	Max	Min	Max		
t _S (H)	Setup Time, HIGH	2.0		2.0		2.0		ns	
t _S (L)	or LOW D _n to CP	2.5		2.5		2.5		113	
t _H (H)	Hold Time, HIGH	1.2		1.4		1.2		ns	
t _H (L)	or LOW D _n to CP	1.2		1.4		1.2		115	
t _W (H)	Pulse Width, CP,	3.3		3.3		3.3		ns	
t _W (L)	HIGH or LOW	3.3		3.3		3.3		115	
t _W (L)	Master Reset Pulse	3.3		3.3		3.3			
	Width, LOW	3.3		3.3		3.3		ns	
t _{REC}	Recovery Time MR to CP	2.0		2.0		2.0		ns	

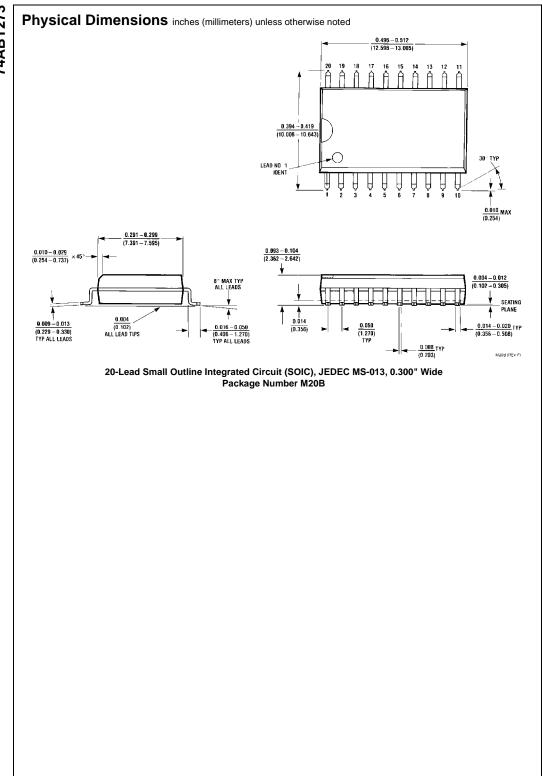
Capacitance

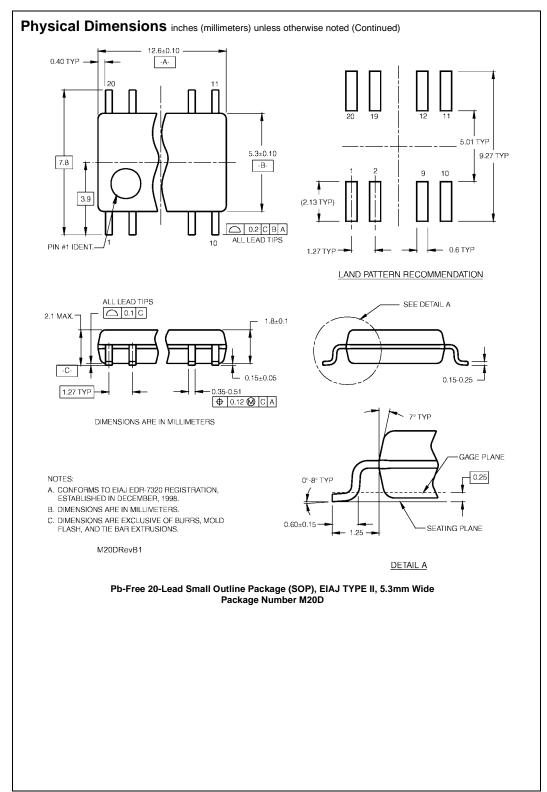
(SOIC package)

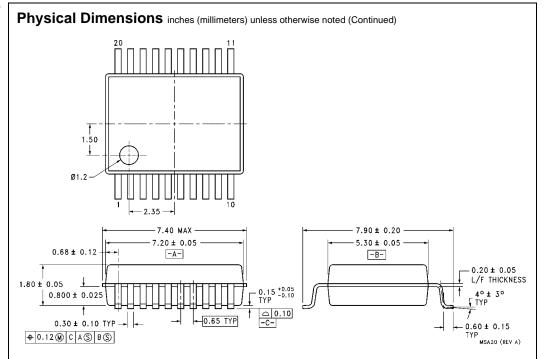
Symbol	Parameter	Тур	Units	Conditions T _A = 25°C
C _{IN}	Input Capacitance	5	pF	V _{CC} = 0V
C _{OUT} (Note 6)	Output Capacitance	9	pF	V _{CC} = 5.0V

Note 6: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-833, Method 3012.



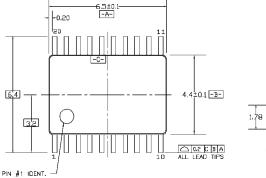


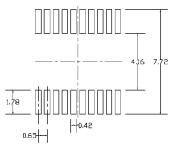




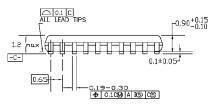
20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide Package Number MSA20

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)





LAND PATTERN RECOMMENDATION





DIMENSIONS ARE IN MILLIMETERS

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MD-153, VARIATION AC, REF NOTE 6, DATE 7/93.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLDS FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ANSI Y14.5M. 1982.

0 - 8°7 GAGE PLANE 0 - 8°7 GAGE PLANE 0.6±0.1 R0.09nin DETAIL A

MTC20REVD1

20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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